

Search Notes

Application/Control No.

10/690,779

Examiner

John S. Chu

Applicant(s)/Patent under
Reexamination

TAKEUCHI ET AL.

Art Unit

1752

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|---------|----------|
| 430 | 138 | 12/2006 | JSC |
| 430 | 157 | 1 | 1 |
| 430 | 176 | 1 | 1 |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|---------|----------|
| 430 | 138 | 12/2006 | JSC |
| 430 | 157 | 1 | 1 |
| 430 | 176 | 1 | 1 |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---------|---------|------|
| UPDATED | 12/2006 | JSC |
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